

**Search Notes**

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Examiner

Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

YAMADA ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner
347	22-35	11/10/2005	SWH
358	296	11/10/2005	SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR